MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PIFD

MJD42C(MS)

Product specification





TRANSISTOR (PNP)

FEATURES

- Designed for General Purpose Amplifier and Low Speed Switching Applications.
- Lead Formed for Surface Mount Applications in Plastic Sleeves
- Electrically Similar to Popular TIP41 and TIP42 Series
- IMonolithic Construction With Built-in Base-Emitter Resistors

Reference News

PACKAGE OUTLINE	Pin Configuration	Marking
1.BASE 2.COLLECTOR 3.EMITTER	COLLECTOR 1 BASE 3 EMITTER	MSKSEMI MJD42C MS XXX

Notes :XXX represents the order code.

MAXIMUM RATINGS (Ta=25 ℃ unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{СВО}	Collector-Base Voltage	-100	V
VCEO	Collector-EmitterVoltage	-100	V
V _{EBO}	Emitter-Base Voltage	-5	V
Ic	Collector Current -Continuous	-6	А
I _{CP} *	Collector Current -Pluse	-10	А
Pc	Collector Power Dissipation	1.25	W
TJ,Tstg	Operating Junction and Storage Temperature Range	-55-150	°C

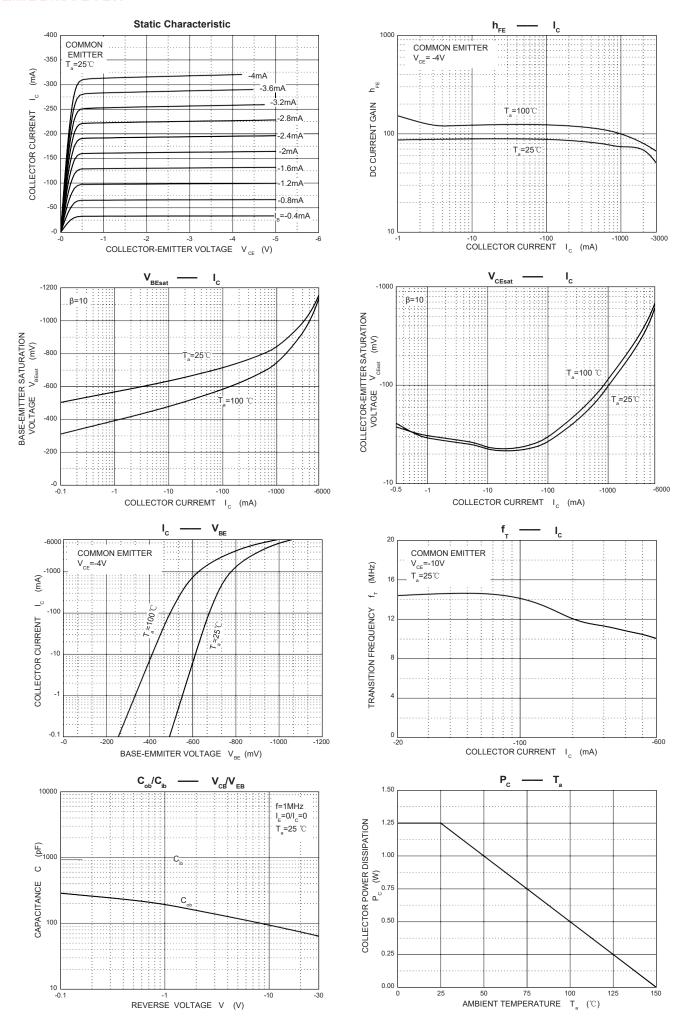


ELECTRICAL CHARACTERISTICS (Ta=25 ℃ unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _(BR) CBO	I _C =-100μA,I _E =0	-100			V
Collector-emitter breakdown voltage	VCEO(sus)	I _C =-30mA,I _B =0	-100			V
Emitter-base breakdown voltage	V _{(BR)EBO}	l _E =-100μA,l _C =0	-5			V
Collector cut-off current	ICEO	V _{CB} =-60V,I _E =0			-50	μA
Emitter cut-off current	I _{EBO}	V _{EB} =-5V I _C =0			-0.5	mA
DC current gain	h _{FE(1)}	V _{CE} =-4V I _C =-0.3A	30			
DC current gain	h _{FE(2)}	V _{CE} =-4V,I _C =-3A	15		75	
Collector-emitter saturation voltage	VCE(sat)	I _C =-6A,I _B =-0.6A			-1.5	V
Base-emitter voltage	V _{BE}	V _{CE} =-4V,I _C =-6A			-2	V
Transition frequency	f⊤	V _{CE} =-10V,I _C =-500mA,f=1MHz	3			MHz

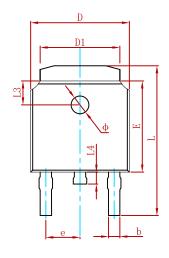
^{*} Pulse Test: PW≤300µs, Duty Cycle≤2%

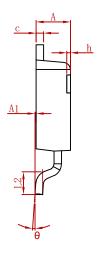


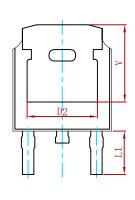




PACKAGE MECHANICAL DATA

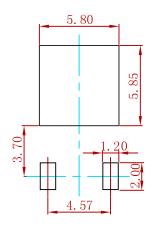






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.635	0.770	0.025	0.030	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830	4.830 REF.		REF.	
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.712	10.312	0.382	0.406	
L1	2.900 REF.		0.114 REF.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 REF.		0.063	REF.	
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.250	5.250 REF.		REF.	

Suggested Pad Layout



Note

- 1. Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MJD42C(MS)	TO-252	2500



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